

RESEARCH PAPER

# Design of 5 GHz low-power CMOS LC VCO based on complementary cross-coupled topology with modified tail current-shaping technique

MENG-TING HSU, PO-HUNG CHEN AND YAO-YEN LEE

*In this paper, a low-power CMOS LC voltage-controlled oscillator (VCO) with body-biasing and low-phase noise with Q-enhancement techniques is presented. A self-body biased circuit is introduced that can reduce power consumption. Some derivations of the Q-enhancement and how to improve the phase noise of the circuit are also discussed. This chip is implemented by the Taiwan Semiconductor Manufacture Company 0.18  $\mu\text{m}$  1P6M process. The measurement results exhibit a tuning range of 14.7% from 4.92 to 5.7 GHz at a supply voltage of 1.4 V. The power consumption of the core circuit and figure of merit are 2.5 mW and  $-188.6$  dBc/Hz. The phase noise is  $-118$  dBc/Hz@1 MHz at an operation frequency of 4.94 GHz.*

**Keywords:** VCO, Low-power, Q-enhancement, Body-biasing

Received 26 September 2013; Revised 23 January 2014; first published online 27 March 2014

## I. INTRODUCTION

Radio-frequency (RF) wireless communication systems that are used to send and receive information are common in modern society. To obtain a more advanced system with lower costs, the integrated circuits must be more highly compacted. In recent years, the CMOS process has been used to design RF circuits, because the process technology has been improved. The front-end RF circuit has been designed to realize system on chip (SoC), which is now possible in the CMOS process [1]. The high performance of a local oscillator (LO) is very important and can stabilize the system as well as increase power transfer from DC to AC signal efficiency in wireless transceivers. Therefore, how to design a high-performance (low-power, wide tuning-range, low-phase noise, and small area) voltage-controlled oscillator (VCO) is an important issue of communication application.

Recently, the low-power LC VCOs topology has been reported [2–7]. There has been much research on low-voltage operation with transformer feedback [3, 4, 7], lower power with body bias [2] or current-reused topology [5] and low-phase noise with Q-improvement techniques [8]. Since lower-power consumption saves energy to enhance the device or

system efficiency, this proposed circuit is designed for low power consumption with the body-biasing technique and low-phase noise with the Q-improvement technique. Analysis and a detailed circuit design of the proposed circuit have been addressed in the paper. The phase noise issues are described in Section II. The proposed VCO topology with formula derivation for negative resistance and body-biasing technique and Q-enhancement is presented in Section III. The measurement results are shown in Section IV. Finally, the conclusion is described in Section V.

## II. PHASE NOISE ISSUE

It was in early 1997 that researchers came to realize a fully integrated LC-tank N-type metal-oxide-semiconductor (NMOS) VCO [9]. In the high-frequency operation regime, the NMOS device is viewed as a high-noise device because of its high density of the majority carriers. Therefore, the P-type metal-oxide-semiconductor (PMOS) device has been replaced by the NMOS to reduce phase noise because of its lower flicker noise at lower frequencies. In addition, the PMOS transistor has lower flicker noise than that of NMOS transistor. This property will give rise to reduce phase noise (by up-conversion) than that of only NMOS transistor VCO. For the purpose of symmetrical signal output swing, the complementary P/N MOS cross couple VCO has good performances than that of only PMOS VCO or NMOS VCO. Of course, the output voltage of signal swing can also reach double ratio with  $V_{DD}$  supply. Therefore, the complementary cross-couple VCO is popular for circuit design

Microwave Communication and Radio Frequency Integrated Circuit Laboratory, Department and Institute of Electronic Engineering, National Yunlin University of Science and Technology, 123 University Road, Section 3, Douliou, Yunlin 64002, Taiwan, Republic of China

**Corresponding author:**

M.-T. Hsu

Email: [hsunt@yuntech.edu.tw](mailto:hsunt@yuntech.edu.tw)

with high performance [10]. But, there are some drawbacks that include an unsymmetrical output signal, switching speed that becomes slower than the NMOS, instability coming from the  $V_{DD}$  variation and interference noise.

Figure 1 is a complementary cross-coupled LC-tank with fixed-bias (FB) tail transistor VCO, which is composed of the NMOS and PMOS cross-coupled pairs. There are three excellent properties as described in the following [10]:

1. Same current existing, so that the complementary cross-coupled pair offers higher transconductance and faster switching speed on each side.
2. The rise-time and the fall-time are more symmetrical to each other, for consideration to prevent the excess noise, which comes from low-frequency noise  $1/f$ , transferring to high frequency.
3. In all NMOS pairs, the channel voltage is higher, which causes a faster saturation speed and a higher  $\gamma$  value ( $\gamma$  is a fabrication-process parameter).

As shown in Fig. 1, M1–M4 consist of a complementary cross-coupled pair, which yields negative resistance to compensate for the loss of the non-ideal LC tank and whose outputs are differential. Figure 1 also shows that the P/N cross-coupled topology can reduce the impulse sensitivity function (ISF) because of its symmetrical output signal. The tail transistor M5 is designed to operate in the saturation region as a current source. Consequently, the tail current determines the oscillation amplitude.

In the VCO, the generation of phase noise results from various reasons. But, there are only certain parts of the noise sources that contribute significantly to the total phase noise [11]. It should be noted that phase noise is not caused mainly by up-conversion or down-conversion. Finally, the tail current source, which is well known, is a large noise source in a VCO. Flicker noise sources will be up-converted to AM noise, and then go into phase noise by amplitude-modulation-to-phase-modulation (AM–PM) conversion of varactors and capacitors dependent on voltage, and thermal noise sources will be converted into phase noise, due to the switching mechanism of the cross-coupled pair as a single-balanced mixer [12]. These noise sources go into output phase noise by up-conversion and down-conversion. Generally, thermal noise will be converted into  $1/f^2$  region, and flicker noise will be converted into  $1/f^3$  region [13]. Table 1 shows the phase noise contribution of each part in the VCO circuit.

The tail transistor source only gave thermal noise in the current-source transistor around the second harmonic of the

Table 1. Phase noise contribution of each part in the VCO circuit.

LC tank noise	4.50%
Cross-couple PMOS noise	12.20%
Cross-couple NMOS noise	31.60%
Current source NMOS noise	51.70%

oscillation. Moreover, high impedance was viewed at the tail that required the stopping of the cross-couple PMOS/NMOS in the triode at the second harmonic from loading the resonator. This suggests that a narrowband circuit is required to suppress the troublesome noise frequencies in the current source, making it appear noiseless to the oscillator, which gives high impedance in the narrow band of frequencies. Therefore, we can put a capacitor into the circuit in parallel with the current source, as shown in Fig. 1 [14]. This technique is also called the tail current-shaping technique for LC-VCO application [15].

Figure 2 shows the self-bias (SB) tail transistor VCO. The operation of the novel oscillator is as follows. Initially, when the circuit is balanced, both the output voltage and current flowing in the two sides are set by the size of the tail transistors. The tail transistors will go into the saturation region first while the cross-coupled NMOS transistors are still in the cutoff region. When both the tail transistors and cross-coupled NMOS transistors are in the triode region, the tail transistors determine the current as the voltages at the source of the cross-coupled NMOS transistors are floating. Since all the transistors in this VCO topology are switched biasing rather than fixed biasing, it is expected to have lower flicker noise [16, 17]. Moreover, as the transistors operate in the triode region for a large portion of the oscillation period, they exhibit lower current flicker noise than the transistors that operate in the saturation region, for example, the tail transistor in the FB topology [18].

In this paper, we added two merits in the circuit. The first is the SB of the tail current transistor and the capacitance ground filter technique, which are combined to improve the phase noise performance. The second is the body-biasing technique of the cross-couple transistor to reduce the power consumption.

### III. CIRCUIT DESIGN

The proposed low-power consumption VCO is realized by the body-biased and Q-enhancement techniques. The schematics of the proposed VCOs are shown in Fig. 3. All those circuits

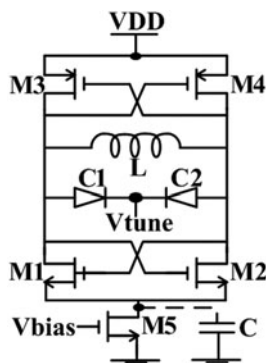


Fig. 1. FB tail transistor VCO with and without capacitor.

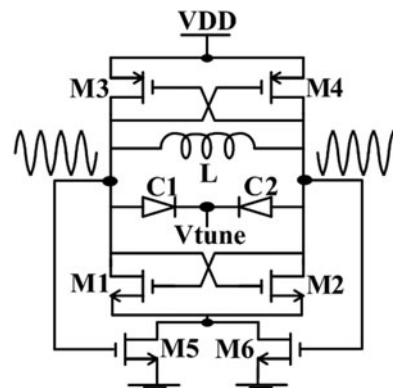


Fig. 2. SB tail transistor VCO.

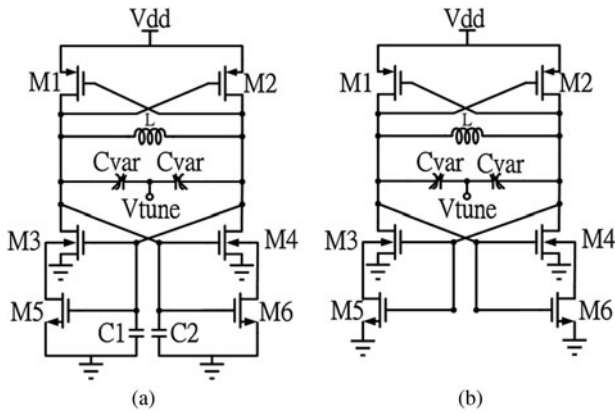


Fig. 3. Schematic diagrams of the two VCOs, (a) chip with Q-enhancement circuit and (b) non-Q-enhancement circuit.

are designed with the body-biasing technique. Figure 3(a) shows the chip with Q-enhancement in terms of capacitors C1/C2 and transistors M3, M4, M5 and M6. Figure 3(b) shows the circuit without Q-enhancement.

**A) LC tank**

The oscillation frequency is generally determined by tanks. The first consideration of LC tanks fabrication is inductor design, which is more difficult than the capacitance. In order to have a wide tuning range, it is desirable for the inductor L to be small compared to the varactor C<sub>var</sub>, and have low parasitic capacitance such as metal-to-substrate capacitance and metal-to-metal capacitance. Furthermore, as the operating frequency is raised, then quality factor Q increases and inductor loss decreases. This VCO uses a two-loop inductor, which can provide enough inductance and also has a high-quality factor for the resonator to operate with fundamental circuit topology from 4.92 to 5.7 GHz. A 0.7 nano-Henry spiral inductor is implemented in this chip. The inductor has a quality factor of approximately 12.3 at the working frequency 5 GHz. The inductance and quality factor of the inductor are shown in Fig. 4.

The capacitance range of the MOS varactor [19] is wider than the junction varactor and the equivalent series resistance of the former is smaller than that of the latter. Because an NMOS varactor does not lie in a P-well, the NMOS varactor is apt to be disturbed in substrate. The concentration of the dopant in the N-well is bigger than that in the P-bulk,

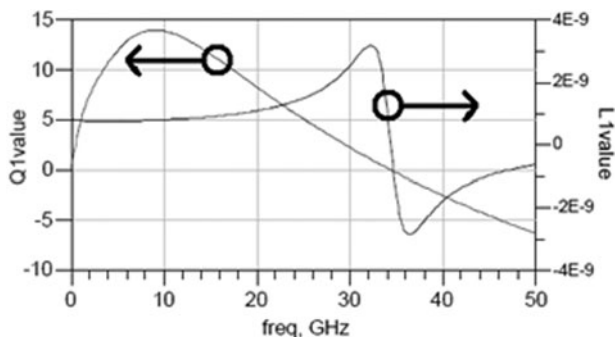


Fig. 4. Inductance and quality factor.

which reduces interference as far as the PMOS varactor is concerned. In view of this, we have adopted the PMOS varactor.

**B) Body-biasing technique**

In many integrated circuit applications, the source terminal is connected to the body (substrate) terminal. According to Adel *et al.* [20], the body-effect equation can be indicated as follows:

$$V_t = V_{to} + \gamma(\sqrt{2\phi_f + V_{sb}} - \sqrt{2\phi_f}) \tag{1}$$

and

$$\gamma = \sqrt{\frac{2qN_A\epsilon_s}{C_{OX}}} \tag{2}$$

where  $V_{to}$  is the threshold voltage for source-body voltage  $V_{sb} = 0$ ;  $\phi_f$  is a physical parameter;  $\gamma$  is a fabrication-process parameter,  $q$  is the electron charge ( $1.6 \times 10^{-19}$  C),  $N_A$  is the doping concentration of a p-type substrate, and  $\epsilon_s$  is the permittivity of silicon. Equation (1) indicates that an incremental change in  $V_{sb}$  will give rise to an incremental change in  $V_t$ . In other words, when the  $V_{sb}$  source-body voltage is reduced, the MOSFET required threshold voltage  $V_t$  is lessened, too. Besides, the MOS current consumption can be reduced. The body-biasing technology can reduce the MOS threshold voltage  $V_t$  to decrease the drain-source current which will produce sufficient transconductance ( $g_m$ ) [2]. Figures 5 and 6 are high-frequency small signal models of MOS. Figure 5 shows the MOS in which the source terminal is connected with the body terminal. The equivalent transconductance ( $g_m$ ) of this MOS model can be indicated as follows [20]:

$$g_m = \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t) \tag{3}$$

without body-biasing technique, the body terminal and source terminal are connected together, so  $V_{bs} = 0$ . Moreover, the body-effect can be ignored. Figure 6 is the high-frequency small signal model of MOS in which the source and body terminal are divided. When a bias voltage is applied to the body

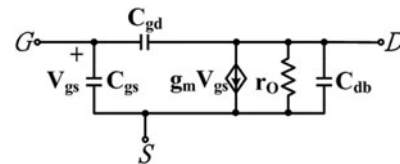


Fig. 5. The case body-source terminal is connected for high-frequency small signal model of MOS.

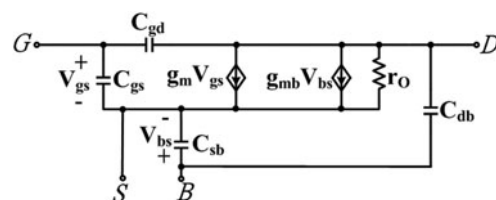


Fig. 6. The case body terminal and source terminal is divided for high-frequency small signal model of MOS.

terminal, then the equivalent transconductance can be rewritten as follows [20]:

$$g_{mb} = \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t) \left( \frac{\gamma}{2\sqrt{2\phi_f - V_{bs}}} \right). \tag{4}$$

Furthermore, it produced extra body-transconductance ( $g_{mb}$ ) in the MOS equivalent transconductance ( $G_m$ ), when the MOS body terminal has the appropriate bias applied. The formula for MOS equivalent transconductance ( $G_m$ ) is shown as follows [21]:

$$G_m = g_m + g_{mb}, \tag{5}$$

where  $g_m$  is MOS transconductance from the  $V_{GS}$  bias,  $g_{mb}$  is MOS body transconductance from the  $V_{bs}$  bias. Compared to the general connect body–source terminal MOS, body-biasing can give larger negative conductance with a less  $V_{GS}$  biased condition. The body-biasing technology also can indirectly improve the VCO phase noise under switched MOS gate conditions [22].

### C) Q-enhancement circuit

The proposed VCO based on complementary cross-coupled topology is shown in Fig. 3(a), the simple schematic of the proposed Q-enhancement circuit is shown in Fig. 7 and its equivalent low-frequency model with body-biasing is shown in Fig. 8.

By considering the equivalent low-frequency model with a body-biased of Q-enhancement circuit (Fig. 8), we have

$$V_X = V_3 - V_4, \tag{6}$$

$$I_X = g_{m4}V_4 + g_{m6}V_4 + g_{mb4}V_{bs4} + sC_1 V_3, \tag{7}$$

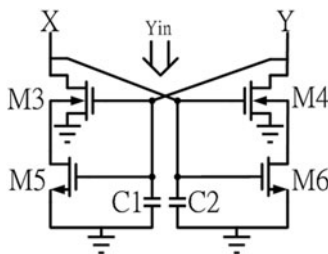


Fig. 7. Simple schematic of proposed Q-enhancement circuit.

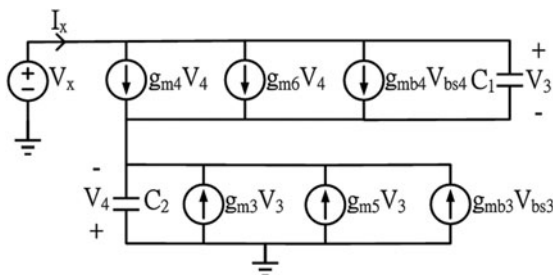


Fig. 8. Equivalent low-frequency model with body-biased of Q-enhancement circuit.

then we have

$$I_X + (g_{m4} + g_{m6})V_X - g_{mb4}V_{bs4} = V_3(g_{m4} + g_{m6} + sC_1) \tag{8}$$

and

$$V_3 = \frac{I_X + (g_{m4} + g_{m6})V_X - g_{mb4}V_{bs4}}{g_{m4} + g_{m6} + sC_1}. \tag{9}$$

In this work, a symmetric structure is adopted, thereby  $g_{m3} = g_{m4} = g_{mx}$ ,  $g_{m5} = g_{m6} = g_{my}$ ,  $sC_1 = sC_2 = sC$ , then (9) becomes (10)

$$V_3 = \frac{I_X + (g_{mx} + g_{my})V_X - g_{mb}V_{bs4}}{g_{mx} + g_{my} + sC}. \tag{10}$$

By the same method, we can obtain (11)

$$V_4 = \frac{I_X + (g_{mx} + g_{my})V_X - g_{mb}V_{bs3}}{g_{mx} + g_{my} + sC}. \tag{11}$$

Substituting (10) and (11) into (6), we obtain

$$V_X = \frac{2I_X + 2(g_{mx} + g_{my})V_X + g_{mb}(V_{bs3} - V_{bs4})}{g_{mx} + g_{my} + sC}. \tag{12}$$

If we assumed that  $V_{bs3} = V_{bs4} = V_{bs}$ , then equation (12) become as (13)

$$V_X = \frac{2I_X + 2(g_{mx} + g_{my})V_X}{g_{mx} + g_{my} + sC}, \tag{13}$$

we can arrange (13) to obtain (14) of input admittance

$$Y_{in} = \frac{I_X}{V_X} = \frac{-(g_{mx} + g_{my}) + sC}{2} \tag{14}$$

substituting  $s = j\omega$  from (14), we can obtain

$$Y_{in} = \frac{-(g_{mx} + g_{my})}{2} + j\frac{\omega C}{2} \tag{15}$$

and

$$Z_{in} = \frac{1}{Y_{in}}. \tag{16}$$

If the admittance  $Y_{in} = G_n + jB_n$  is taken into equation (16), then we can have the following equation:

$$Z_{in} = \frac{1}{G_n + jB_n} \tag{17}$$

where

$$G_n = -\frac{g_{mx} + g_{my}}{2} \tag{18}$$

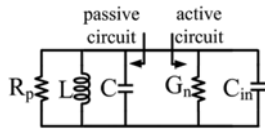


Fig. 9. One-port equivalent circuit of VCO between passive and active circuit.

is the real part of the admittance of the active circuit, and

$$jB_n = s \frac{C}{2} = sC_{in} \tag{19}$$

is the imaginary part of the admittance of the active circuit.

Figure 9 shows the one-port equivalent circuit of the general VCO between passive and active circuits.  $G_n$  indicates the negative transconductance of  $M_3/M_4$  NMOS transistor with the low-frequency model. Assume that the resistance of the LC tank is represented  $R_p$ , which is in parallel with the LC resonance circuit, then the start-up condition of the proposed VCO can be obtained as the following equation:

$$R_p + G_n \leq 0. \tag{20}$$

The oscillation frequency  $\omega_o$  with Fig. 9 also can be calculated by the following equation:

$$\omega_o = \frac{1}{\sqrt{L(C_{var} + C_{in})}}, \tag{21}$$

where  $C_{var}$  is the varactor capacitor and equivalent capacitor  $C_{in}$  is the input capacitor of the proposed VCO with active circuit, then the Q of proposed VCO is the following [8]:

$$Q \approx \frac{1}{G_{total}} \sqrt{\frac{C_{total}}{L}}, \tag{22}$$

where  $C_{total}$  is the total capacitance of VCO,  $G_{total}$  is the total conductance of VCO, and  $L$  is the inductance of the VCO. Therefore, the VCO total conductance is the following:

$$G_{total} = G_{loss} + G_n \approx G_{loss} - \frac{g_{mx} + g_{my}}{2}, \tag{23}$$

where  $G_{loss}$  is the parasitic loss conductance of inductor  $L$ ,  $G_n$  is the conductance of NMOS cross-couple pair ( $M_3, M_4$ ).

From equation (22), as  $G_{total}$  is reduced, then Q of the proposed VCO is increased. Furthermore, the VCO phase noise can be reduced when the quality factor is increased. From Figs 3(a) and 3(b), we observe that the phase noise of the

Table 2. Equivalent element value.

	Prop. VCO	No-Q VCO
$Q_{Load}$	10.25	2.29
$G_T$	3.71 mS	16.1 mS
$C_T$	1.1 pF	1.03 pF
$L$	0.76 nH	0.76 nH

Prop. VCO is proposed VCO, and No-Q VCO is without Q-improvement technique VCO.

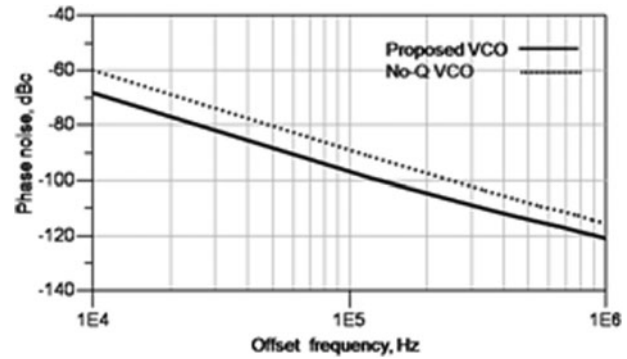


Fig. 10. Simulated phase noise of proposed VCO and without Q-improvement technique VCO at 5.1 GHz.

Table 3. Phase noise of VCO.

Offset freq.	10 kHz	100 kHz	1 MHz
Prop. VCO	-68.3 dBc	-95.9 dBc	-120.7 dBc
No-Q VCO	-59.9 dBc	-89.2 dBc	-115.5 dBc

proposed VCO can be improved with the Q-enhancement technique, and the results are shown in Table 2, Fig. 10 and Table 3.

Table 2 shows the variation between the VCO with and without Q-enhancement. Figure 10 and Table 3 indicate that the phase noise performance of proposed VCO is better than that of it without Q-enhancement.

#### IV. MEASUREMENT RESULTS

The proposed VCOs were fabricated by Taiwan Semiconductor Manufacture Company (TSMC) 0.18- $\mu\text{m}$  1P6M CMOS technology. An Agilent E5052A signal source analyzer, which administered two DC sources to the supply voltage and control voltage, was used to measure the output frequency, power, phase noise, and output spectrum. The buffers are included on-chip to facilitate driving a 50- $\Omega$  environment. Each buffer consists of PMOS transistors and is biased with an external Bias-Tee. The differential outputs connect a Bias-Tee on each side with two loads, Agilent 5052A and 50  $\Omega$ .

The die photographs of the chip are shown in Fig. 11. The chip area is  $0.692 \times 0.537$  ( $\text{mm}^2$ ). The measured phase noise, output signal spectrum, and frequency-tuning range of the chip are shown in Figs 12–14, respectively. The measured phase noise is -118.05 dBc/Hz at 1 MHz offset from the carrier frequency 4.94 GHz as shown in Fig. 11. The signal output power is about -22 dBm as shown in Fig. 13. The frequency-tuning range is between 4.92 and 5.7 GHz, which achieved a 14.7% tuning range and which is measured from -0.5 to 2 V as shown in Fig. 14. The core power dissipation of the VCO is 2.5 mW with 1.4 V supply voltage.

It is well known that the figure of merit (FOM) is an index between different VCOs [23]. The  $FOM$  and  $FOM_t$  are defined as follows:

$$FOM = 10 \log \left[ \left( \frac{\omega_o}{\Delta\omega} \right)^2 \cdot \frac{1}{L\{\Delta\omega\} \cdot P_{dc}} \right], \tag{24}$$



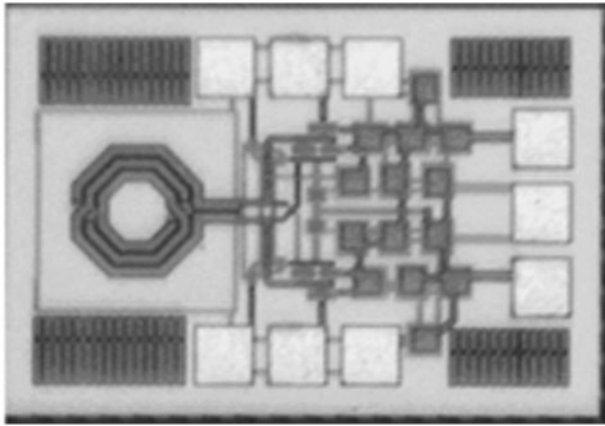


Fig. 11. Chip photos.

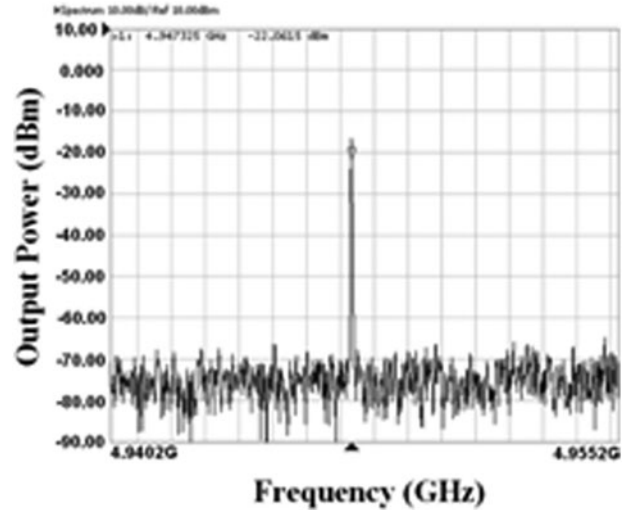


Fig. 13. Output spectrum.

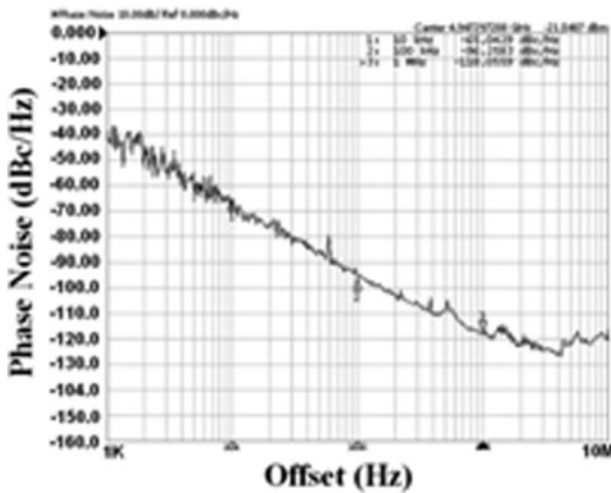


Fig. 12. Measured phase noise.

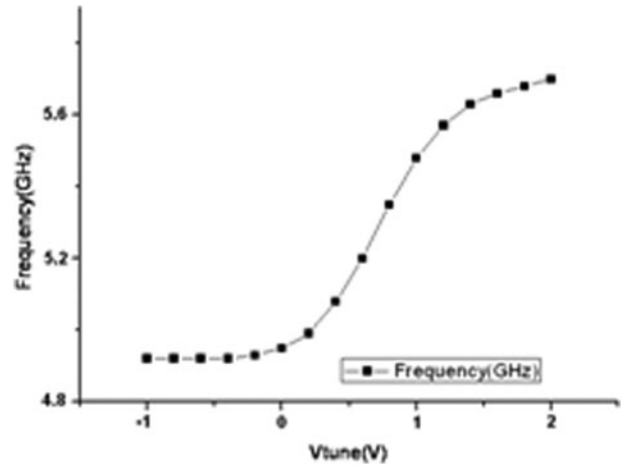


Fig. 14. Frequency-tuning range.

$$FOM_t = FOM - 20 \log \left[ \frac{FTR}{10} \right], \quad (25)$$

where  $\omega_0$  is the center frequency,  $\Delta\omega$  is the frequency offset,  $L\{\Delta\omega\}$  is the phase noise at  $\Delta\omega$ ,  $P_{dc}$  is the dc power consumption. FTR is the frequency-tuning range.

The parameter of our chips and recently reported papers are summarized in Table 4. Most of the VCOs have high FOM of more than  $-185$  dBc/Hz. Focusing on core power dissipation of the VCOs, our work shows good performance for low power applications.

Table 4. Comparison of VCO performance.

Reference	[24]	[25]	[26]	[27]	[28]	[29]	[30]	[31]	This work [32]
Process ( $\mu\text{m}$ )	0.18	0.18	0.18	0.18	0.18	0.18	0.18	0.18	0.18
Center frequency (GHz)	5	5.46	5.32	5.6	21.37	12.77	2.43	2.42	5.31
Supply voltage (V)	1.5	1.8	1.2	1.2	0.6	0.4	0.6	0.5	1.4
Core power dissipation (mW)	3	6.4	5.71	2.3	3.5	1.08	0.65	0.2	2.5
Phase noise @1 MHz (dBc/Hz)	-120.4	-120.3	-116	-119.1	-109.8	-110.19	-114	-115.8	-118
Tuning range (%)	8.3	10.6	4.9	10.7	5.1	5.75	9.1	7.3	14.7
FOM (dBc/Hz)	-189.6	-187	-183.1	-190.4	-190.9	-192	-183.4	-190.5	-188.6
FOM <sub>t</sub> (dBc/Hz)	-187.9	-187.5	-176.9	-191	-185.1	-187.2	-182.6	-187.8	-191.9
Topology	1*&2*	1*&2*	4*	1*&5*	3*&5*&6*	3*&5*&6*	3*&6*	3*&6*	4*&7*

1\*, Copitts; 2\*, PMOS cross-coupled; 3\*, NMOS cross-coupled; 4\*, P-NMOS cross-coupled; 5\*, Transformer; 6\*, Body-biasing; 7\*, Tail current-shaping technique and body biasing.

## V. CONCLUSION

This chip that was adopted using the body-biasing and Q-enhancement techniques for low-power consumption and low-phase noise design has been presented. This chip was implemented in standard 0.18- $\mu\text{m}$  CMOS processes of TSMC. The measurement results show the phase noise  $-118$  dBc/Hz at 1 MHz offset frequency from 4.94 GHz. The core power consumption is 2.5 mW. The FOM of our work shows good performance comparable with other papers in the literature.

## ACKNOWLEDGEMENTS

The authors thank the Taiwan Semiconductor Manufacture Company (TSMC) and National Chip Implementation Center (CIC) for the wafer fabrications and IC measurements. This project is supported by the National Science Council (NSC 101-2221-E-224-049-).

## REFERENCES

- [1] Abidi, A.A.: Wireless transceivers in CMOS IC technology. The new wave, in 1999 Int. Symp. on VLSI Technology, Systems, and Applications, 1999, 151–158.
- [2] Park, D.; Cho, S.H.: Design techniques for a low-voltage VCO with wide tuning range and low sensitivity to environmental variations. *IEEE Trans. Microw. Theory Tech.*, **57** (2009), 767–774.
- [3] Hsu, M.-T.; Huang, Y.-H.: A low phase noise and low power CMOS VCO with transformer feedback, in 2009 Asia Pacific Microwave Conf. (APMC 2009), 2009, 2280–2283.
- [4] Chiu, Y.-T.; Lin, C.-H.; Chang, H.-Y.: Design and analysis of two modified Colpitts VCOS with and without transformer feedback, in 2011 Eur. Microwave Integrated Circuits Conf. (EuMIC), 2011, 430–433.
- [5] Chuang, Y.-H.; Jang, S.-L.; Senior, Lee, S.-H.; Yen, R.-H.; Jhao, J.-J.: 5-GHz low power current-reused balanced CMOS differential armstrong VCOS. *IEEE Microw. Wirel. Compon. Lett.*, **17** (2007), 139–141.
- [6] Nagarajan, M.; Ma, K.; Seng, Y.K.; Mou, S.X.; Kumar, T.B.: A low power wide tuning range low phase noise VCO using coupled LC tanks, in 2011 Semiconductor Conf. Dresden (SCD), 2011, 1–4.
- [7] Kwok, K.; Luong, H.C.: Ultra-low-voltage high-performance CMOS VCOS using transformer feedback. *IEEE J. Solid-State Circuits*, **40** (2005), 652–660.
- [8] Park, B.; Lee, S.; Choi, S.; Hong, S.: A 12-GHz fully integrated cascode CMOS LC VCO with Q-enhancement circuit. *IEEE Microw. Wirel. Compon. Lett.*, **18** (2008), 133–135.
- [9] Craninckx, J.; Steyaert, M.: A 1.8-GHz low-phase-noise CMOS VCO using optimized hollow spiral inductors. *IEEE J. Solid-State Circuits*, **32** (1997), 736–744.
- [10] Han, D.; Hajimiri, A.: Concepts and methods in optimization of integrated LC VCOS. *IEEE J. Solid-State Circuits*, **36** (2001), 896–909.
- [11] Rael, J.J.; Abidi, A.A.: Physical processes of phase noise in differential LC oscillators, in Proc. IEEE Custom Integrated Circuits Conf., Orlando, FL, 2000, 569–572.
- [12] Hegazi, E.; Sjolund, H.; Abidi, A.A.: A filtering technique to lower LC oscillator phase noise. *IEEE J. Solid-State Circuits*, **36** (12) (2001), 1921.
- [13] Hajimiri, A.; Lee, T.H.: A general theory of phase noise in electrical oscillators. *IEEE J. Solid-State Circuits*, **33** (2) (1998), 179–194.
- [14] Hegazi, E.; Sjolund, H.; Abidi, A.: A filtering technique to lower oscillator phase noise. *IEEE J. Solid-State Circuits*, **SC-36** (2001), 1921–1930.
- [15] Soltanian, B.; Kinget, P.R.: Tail current-shaping to improve phase noise in LC voltage-controlled oscillators. *IEEE J. Solid-State Circuits*, **41** (2006), 1792–1802.
- [16] Klumperink, E.A.M.; Gierkink, S.L.J.; van der Wel, A.P.; Nauta, B.: Reducing MOSFET 1/f noise and power consumption by switch biasing. *IEEE J. Solid-State Circuits*, **35** (2000), 994–1001.
- [17] Gierkink, S.L.J.; Klumperink, E.A.M.; van der Wel, A.P.; Hoogzaad, G.; van Tuijl, E.; Nauta, B.: Intrinsic 1/f device noise reduction and its effect on phase noise in CMOS ring oscillators. *IEEE J. Solid-State Circuits*, **34** (1999), 1022–1025.
- [18] Hung, K.K.; Ko, P.; Hu, C.; Cheng, Y.C.: A physics-based MOSFET noise model for circuit simulators. *IEEE Trans. Electron Devices*, **37** (1990), 1323–1333.
- [19] Andreani, P.; Mattisson, S.: On the use of MOS varactors in RF VCO's. *IEEE J. Solid-State Circuits*, **35** (6) (2000), 905–910.
- [20] Adel, K.C.S.; Sedra, S.: *Microelectronic Circuits*: Oxford University Press, USA, 2004, 258–259.
- [21] Allen, P.E.; Holberg, D.R.: *CMOS Analog Circuit Design*, 2nd ed., Oxford University Press, USA, 2002.
- [22] Šiprak, D.; Zanolli, N.; Tiebout, M.; Baumgartner, P.; Fiegna, C.: Reduction of low-frequency noise in MOSFETs under switched gate and substrate bias, in 2008 38th European Solid-State Device Research Conf. (ESSDERC 2008), 2008, 266–269.
- [23] Samori, C.; Lacaita, A.L.; Villa, F.; Zappa, F.: Spectrum folding and phase noise in LC tuned oscillators. *IEEE Trans. Circuits Syst. II*, **45** (1998), 781–790.
- [24] Tsai, M.-D.; Cho, Y.-H.; Wang, H.: A 5-GHz low phase noise differential colpitts CMOS VCO. *IEEE Microw. Wirel. Compon. Lett.*, **15** (5) (2005), 327–329.
- [25] Hou, J.-A.; Wang, Y.-H.: A 5 GHz differential colpitts CMOS VCO using the bottom PMOS cross-coupled current source. *IEEE Microw. Wirel. Compon. Lett.*, **19** (2009), 401–403.
- [26] Yijoo, S. et al.: A low phase noise fully integrated CMOS LC VCO using a large gate length pMOS current source and bias filtering technique for 5-GHz WLAN, in 2007 Int. Symp. on Signals, Systems and Electronics (ISSSE '07), 2007, 521–524.
- [27] Sheng-Lyang, J. et al.: A 5.6 GHz low power balanced VCO in 0.18  $\mu\text{m}$  CMOS. *IEEE Microw. Wirel. Compon. Lett.*, **19** (2009), 233–235.
- [28] Liu, S.-L.; Chen, K.-H.; Chang, T.; Chin, A.: A low-power K-band CMOS VCO with four-coil transformer feedback. *IEEE Microw. Wirel. Compon. Lett.*, **20** (8) (2010), 459–461.
- [29] Wang, T.-P.; Li, C.-C.: A 0.4-V 1.08-mW 12-GHz high-performance VCO in 0.18- $\mu\text{m}$  CMOS, in 2012 IEEE Radio and Wireless Symp. (RWS), 207–210.
- [30] Wang, C.; Huang, L.; Chen, N.; Ye, T.; Lin, F.: A 0.65 mW 2.3–2.5 GHz low phase noise LC-VCO with adaptive body biasing technique, in 2011 IEEE Int. Symp. Radio-Frequency Integration Technology (RFIT), 201–214.
- [31] Park, D.; Cho, S.: An adaptive body-biased VCO with voltage-boosted switched tuning in 0.5-V supply, in 2006 Proc. 32nd Eur. Solid-State Circuits Conf. (ESSCIRC 2006), 444–447.
- [32] Hsu, M.-T.; Huang, J.-A.: Design a 5 GHz low power CMOS LC VCO for IEEE 802.11a application, in 2010 Asia-Pacific Microwave Conf. Proc. (APMC), 2010, 453–456.



**Meng-Ting Hsu** was born in Changhua, Taiwan, Republic of China in 1961. He received his B.S. and M.S. degrees from Chung-Yuan Christian University in the Electrical and Electronic Engineering in 1989 and 1991, respectively. Since 1992 he has served as a Lecturer in the Electronic Department of National Yunlin University of Science & Tech-

nology (NYUST), and he later obtained a Ph.D. degree from National Chiao-Tung University in Communication Engineering in 2004. In 2005, he was promoted to Associate Professor and has more than 15 years experience in microwave circuit design. His current research interests are in noise theory application on MMIC and CMOS RFICs. He is also active on RF UWB design. He is the Vice Dean of Electronic Department of NYUST from August 2011.



**Po-Hung Chen** was born in Yunlin, Taiwan, Republic of China in 1987. He received the B.S. degree in Electrical Engineering from Nation Changhua University of Education in 2009. Then, he obtained an M.S. degree from National Yunlin University of Science & Technology (NYUST) in Electric Engineering in July 2011. His present

research interests are in RF-integrated circuit design.



**Yao-Yen Lee** was born in Taipei, Taiwan, Republic of China in 1987. He received the B.S. degree in Electrical Engineering from Kun Shan University in 2009. He pursues M.S. degree in the National Yunlin University of Science & Technology in Electric Engineering from 2012. His current research interests in CMOS RFICs.